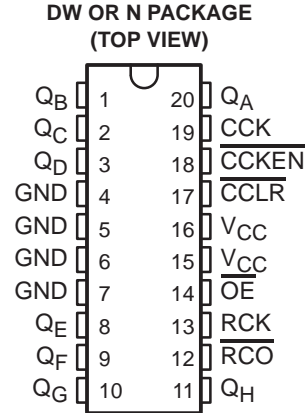


**74AC11590**  
**8-BIT BINARY COUNTER**  
**WITH REGISTERED 3-STATE OUTPUTS**  
SCAS194 – D3988, MARCH 1992 – REVISED APRIL 1993

- Parallel Registered Outputs
- Internal Counters Have Direct Clear
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin  $V_{CC}$  and GND Configurations Minimize High-Speed Switching Noise
- **EPIC™** (Enhanced-Performance Implanted CMOS) 1- $\mu$ m Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs



## description

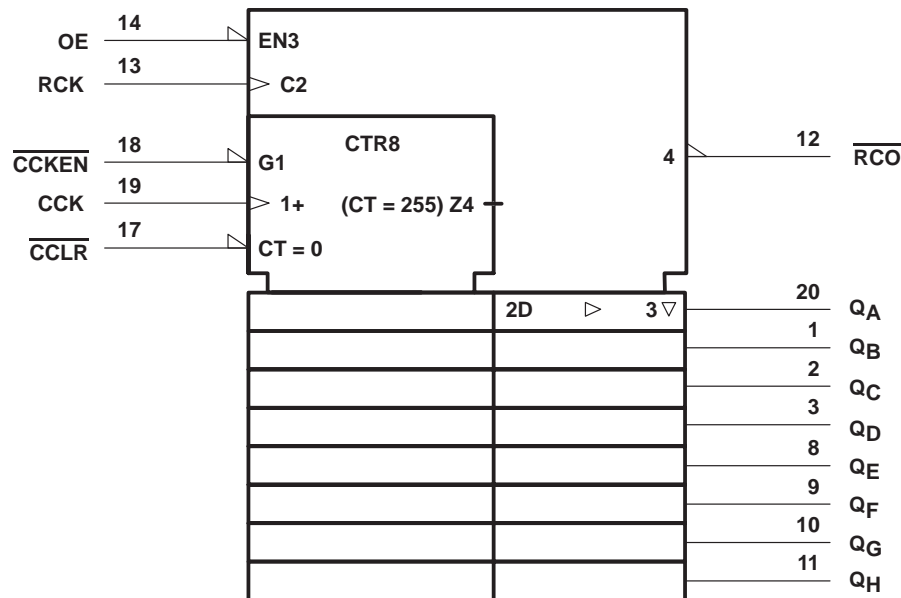
The 74AC11590 contains an 8-bit binary counter that feeds an 8-bit storage register. The storage register has parallel outputs. Separate clocks are provided for both the binary counter and storage register.

The binary counter features a direct clear ( $\overline{CCLR}$ ) input and a count-enable ( $\overline{CCKEN}$ ) input. For cascading, a ripple-carry ( $\overline{RCO}$ ) output is provided. Expansion is easily accomplished for two stages by connecting  $\overline{RCO}$  of the first stage to  $\overline{CCKEN}$  of the second stage. Cascading for larger count chains can be accomplished by connecting  $\overline{RCO}$  of each stage to CCK of the following stage.

Both the register and the counter have individual positive-edge-triggered clocks. If both clocks are connected together, the counter state is always one count ahead of the register. Internal circuitry prevents clocking from the clock enable.

The 74AC11590 is characterized for operation from –40°C to 85°C.

## logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



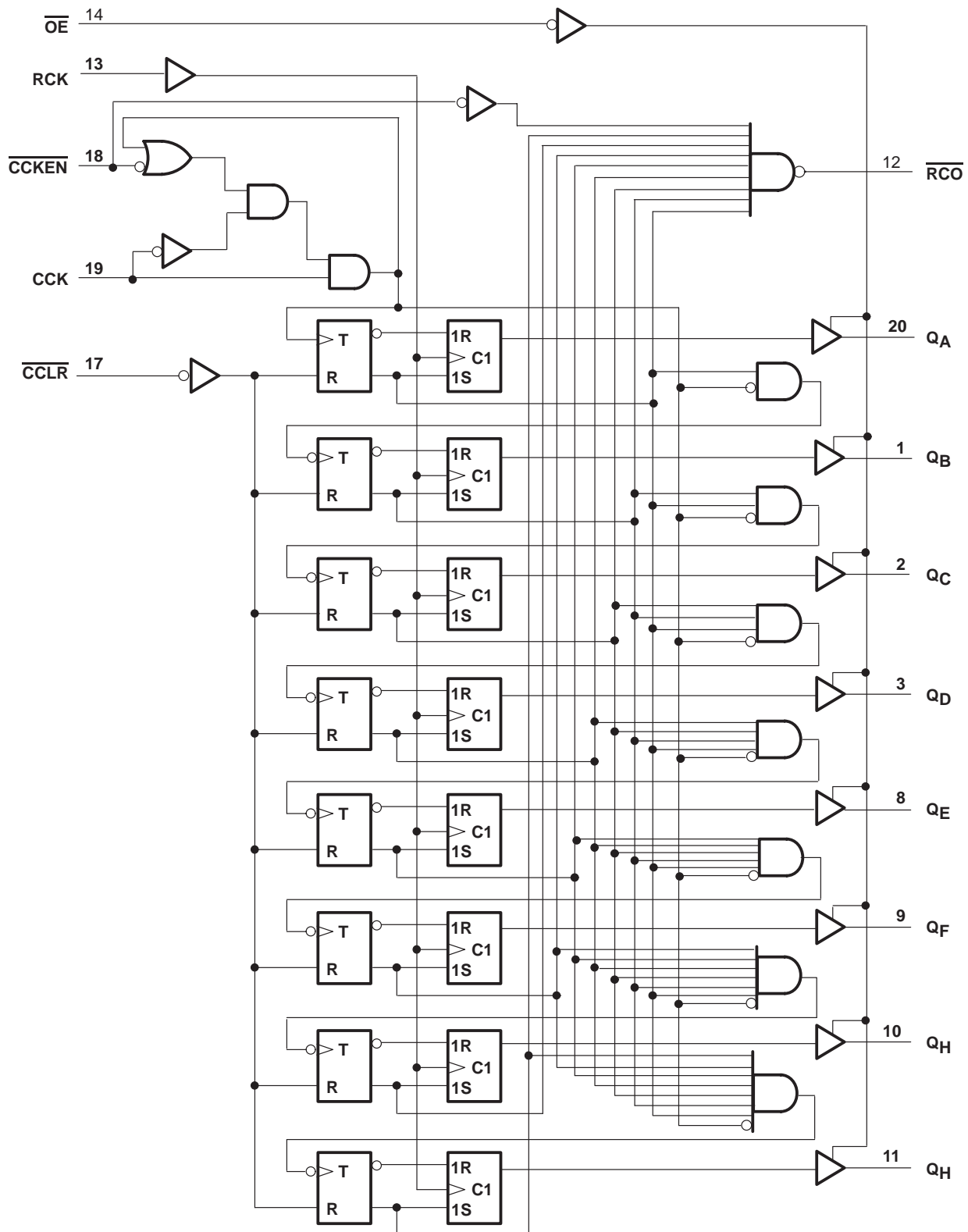
# 74AC11590

## 8-BIT BINARY COUNTER

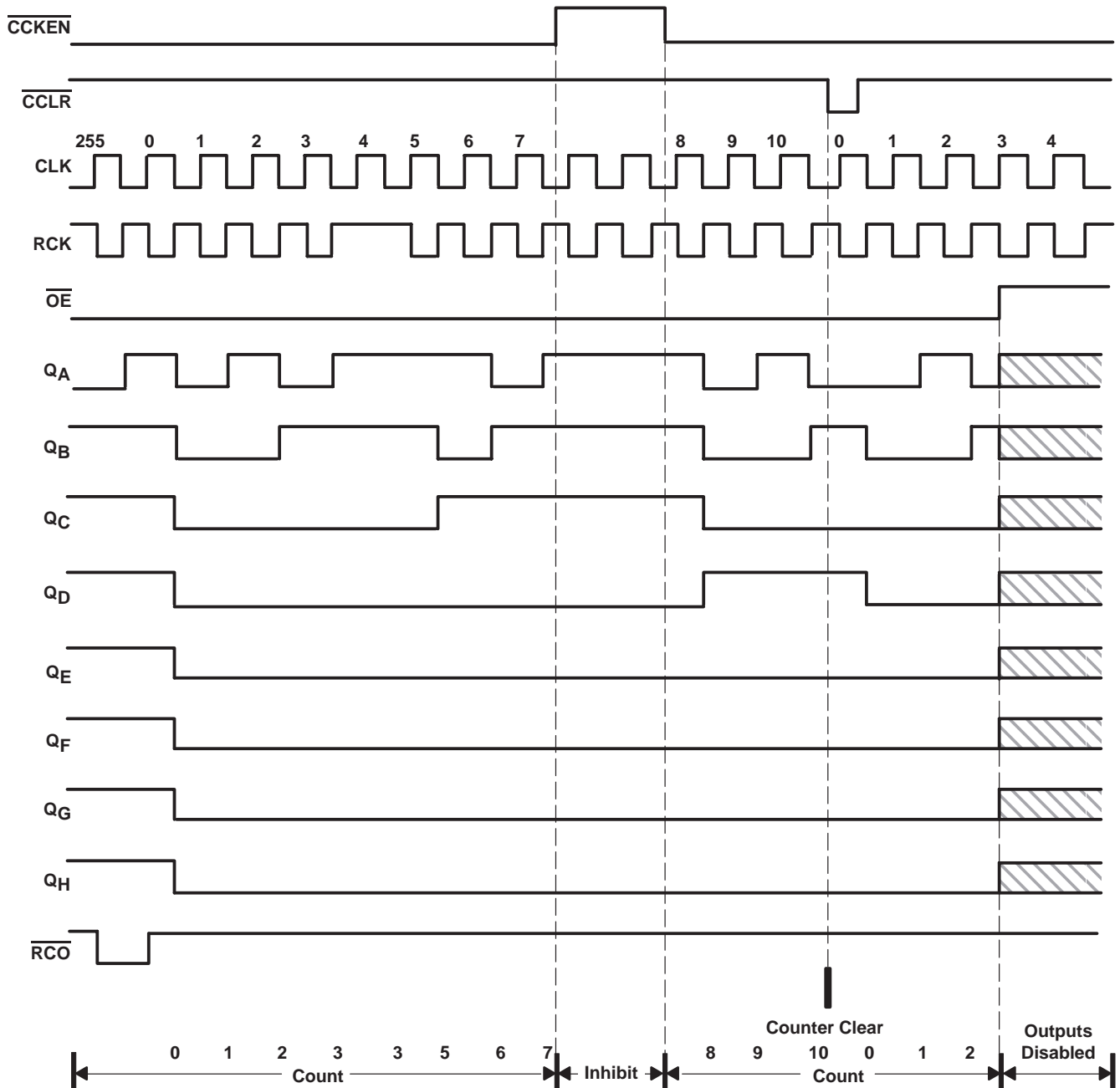
### WITH REGISTERED 3-STATE OUTPUTS

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#### logic diagram (positive logic)



**typical operating sequence**



# 74AC11590

## 8-BIT BINARY COUNTER

### WITH REGISTERED 3-STATE OUTPUTS

SCAS194 – D3988, MARCH 1992 – REVISED APRIL 1993

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$	–0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, $V_O$ (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through $V_{CC}$ or GND	±225 mA
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

#### recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
$V_{CC}$	Supply voltage	3	5	5.5	V
$V_{IH}$	High-level input voltage	$V_{CC} = 3$ V		2.1	V
		$V_{CC} = 4.5$ V		3.15	
		$V_{CC} = 5.5$ V		3.85	
$V_{IL}$	Low-level input voltage	$V_{CC} = 3$ V		0.9	V
		$V_{CC} = 4.5$ V		1.35	
		$V_{CC} = 5.5$ V		1.65	
$V_I$	Input voltage	0		$V_{CC}$	V
$V_O$	Output voltage	0		$V_{CC}$	V
$I_{OH}$	High-level output current	$V_{CC} = 3$ V		–4	mA
		$V_{CC} = 4.5$ V		–24	
		$V_{CC} = 5.5$ V		–24	
$I_{OL}$	Low-level output current	$V_{CC} = 3$ V		12	mA
		$V_{CC} = 4.5$ V		24	
		$V_{CC} = 5.5$ V		24	
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
$T_A$	Operating free-air temperature	–40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V <sub>OH</sub>	I <sub>OH</sub> = – 50 µA	3 V	2.9			2.9		V
		4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
	I <sub>OH</sub> = – 4 mA	3 V	2.58			2.48		
		4.5 V	3.94			3.8		
		5.5 V	4.94			4.8		
	I <sub>OH</sub> = – 75 mA†	5.5 V				3.85		
V <sub>OL</sub>	I <sub>OL</sub> = 50 µA	3 V	0.1			0.1		V
		4.5 V	0.1			0.1		
		5.5 V	0.1			0.1		
	I <sub>OL</sub> = 12 mA	3 V	0.36			0.44		
		4.5 V	0.36			0.44		
		5.5 V	0.36			0.44		
	I <sub>OL</sub> = 75 mA†	5.5 V				1.65		
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V	±0.1			±1		µA
I <sub>OZ</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5 V	±0.5			±5		µA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	5.5 V	8			80		µA
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V	3					pF
C <sub>o</sub>	V <sub>O</sub> = V <sub>CC</sub> or GND	5 V	11					pF

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V<sub>CC</sub> = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		MIN	MAX	UNIT
		MIN	MAX			
f <sub>clock</sub>	Clock frequency, CCK or RCK	0	50	0	50	MHz
t <sub>w</sub>	CCK or RCK high or low	10		10		ns
	CCLR low	7.4		7.4		
t <sub>su</sub>	CCKEN low before CCK↑	5.2		5.2		ns
	CCLR high before CCK↑	3.4		3.4		
	CCK↑ before RCK↑‡	8.1		8.1		
t <sub>h</sub>	CCKEN low after CCK↑	0		0		ns

‡ This setup time ensures that the register will see stable data from the counter outputs. The clocks may be tied together, in which case the register will be one clock pulse behind the counter.

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**timing requirements over recommended operating free-air temperature range,  $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$  (unless otherwise noted) (see Figure 1)**

			T <sub>A</sub> = 25°C		MIN	MAX	UNIT
			MIN	MAX			
f <sub>clock</sub>	Clock frequency, CCK or RCK		0	80	0	80	MHz
t <sub>w</sub>	Pulse duration	CCK or RCK high or low	6.3		6.3		ns
		CCLR low	4.9		4.9		
t <sub>su</sub>	Setup time	CCKEN low before CCK↑	3.7		3.7		ns
		CCLR high before CCK↑	1.6		1.6		
		CCK↑ before RCK↑↑	5.5		5.5		
t <sub>h</sub>	Hold time	CCKEN low after CCK↑	0.5		0.5		ns

$\uparrow$  This setup time ensures that the register will see stable data from the counter outputs. The clocks may be tied together, in which case the register will be one clock pulse behind the counter.

**switching characteristics over recommended operating free-air temperature range,  $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$  (unless otherwise noted) (see Figure 1)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
f <sub>max</sub>	CCK or RCK		50			50		MHz
t <sub>PLH</sub>	CCK	$\overline{\text{RCO}}$	7	13.5	15.9	7	18.3	ns
t <sub>PHL</sub>			9	16.9	19.5	9	22.1	
t <sub>PLH</sub>	$\overline{\text{CCLR}}$	$\overline{\text{RCO}}$	6.2	12.4	14.8	6.2	17.1	ns
t <sub>PLH</sub>	RCK	Q	7.3	13.7	16.2	7.3	18.7	ns
t <sub>PHL</sub>			7	13.6	15.9	7	17.9	
t <sub>PZH</sub>	$\overline{\text{OE}}$	Q	7.8	15.5	18.5	7.8	21.1	ns
t <sub>PZL</sub>			8.5	18.2	21.4	8.5	24.5	
t <sub>PHZ</sub>	$\overline{\text{OE}}$	Q	6.3	10	11.9	6.3	13.2	ns
t <sub>PLZ</sub>			6.8	10.8	12.8	6.8	14.1	
t <sub>PLH</sub>	$\overline{\text{CCKEN}}$	$\overline{\text{RCO}}$	6	11.7	14	6	16.2	ns
t <sub>PHL</sub>			6	11.6	13.7	6	15.4	

**switching characteristics over recommended operating free-air temperature range,  $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$  (unless otherwise noted) (see Figure 1)**

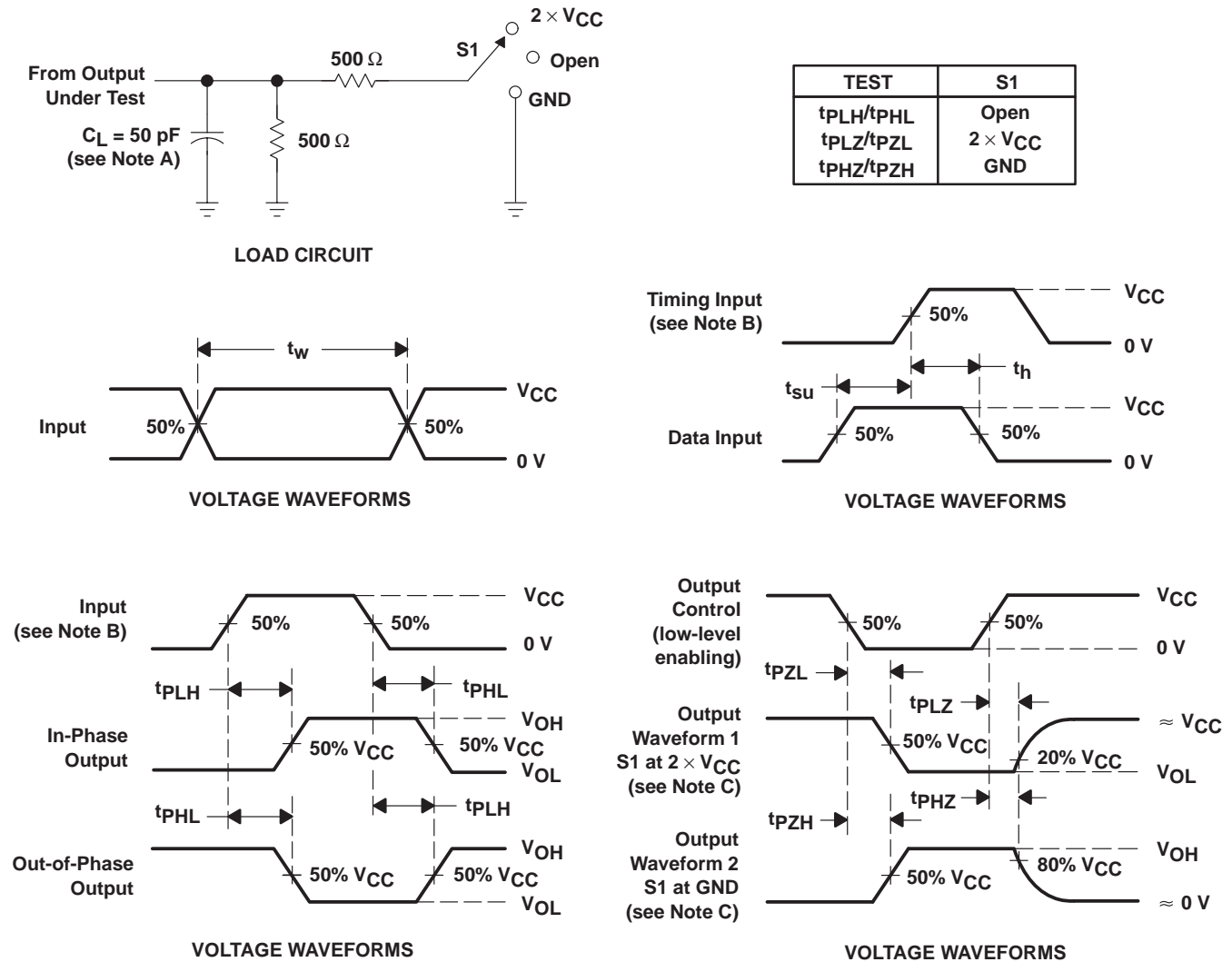
PARAMETER	FROM (INPUT)	TO (OUTPUT)	T <sub>A</sub> = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
f <sub>max</sub>	CCK or RCK		80			80		MHz
t <sub>PLH</sub>	CCK	RCO	3.6	7.8	10.2	3.6	11.7	ns
t <sub>PHL</sub>			4.7	9.8	12.7	4.7	14.4	
t <sub>PLH</sub>	$\overline{\text{CCLR}}$	$\overline{\text{RCO}}$	3.2	7.2	9.5	3.2	10.9	ns
t <sub>PLH</sub>	RCK	Q	3.7	8	10.4	3.7	12	ns
t <sub>PHL</sub>			3.6	8.2	10.7	3.6	12.1	
t <sub>PZH</sub>	OE	Q	3.8	8.9	11.9	3.8	13.6	ns
t <sub>PZL</sub>			3.7	9.5	12.6	3.7	14.3	
t <sub>PHZ</sub>	OE	Q	4.5	7.5	9.4	4.5	10.5	ns
t <sub>PLZ</sub>			5.4	8.7	10.8	5.4	12	
t <sub>PLH</sub>	$\overline{\text{CCKEN}}$	$\overline{\text{RCO}}$	3	6.9	9	3	10.4	ns
t <sub>PHL</sub>			2.9	7	9.2	2.9	10.4	



operating characteristics,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
$C_{pd}$ Power dissipation capacitance	Outputs enabled	$C_L = 50\text{ pF}$ , $f = 1\text{ MHz}$	66	pF
	Outputs disabled		43	

### PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r = 3\text{ ns}$ ,  $t_f = 3\text{ ns}$ .  
 C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.  
 Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 D. The outputs are measured one at a time with one input transition per measurement.

**Figure 1. Load Circuit and Voltage Waveforms**





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